

# High rate capability of gas ionization chamber with flash ADC

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# Collaborators...

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Taguchi,<sup>2</sup> D. Watanabe, **Z. Yifan**, **T. Yoshinobu**,  
and H307 and H314 collaborations

# Introduction

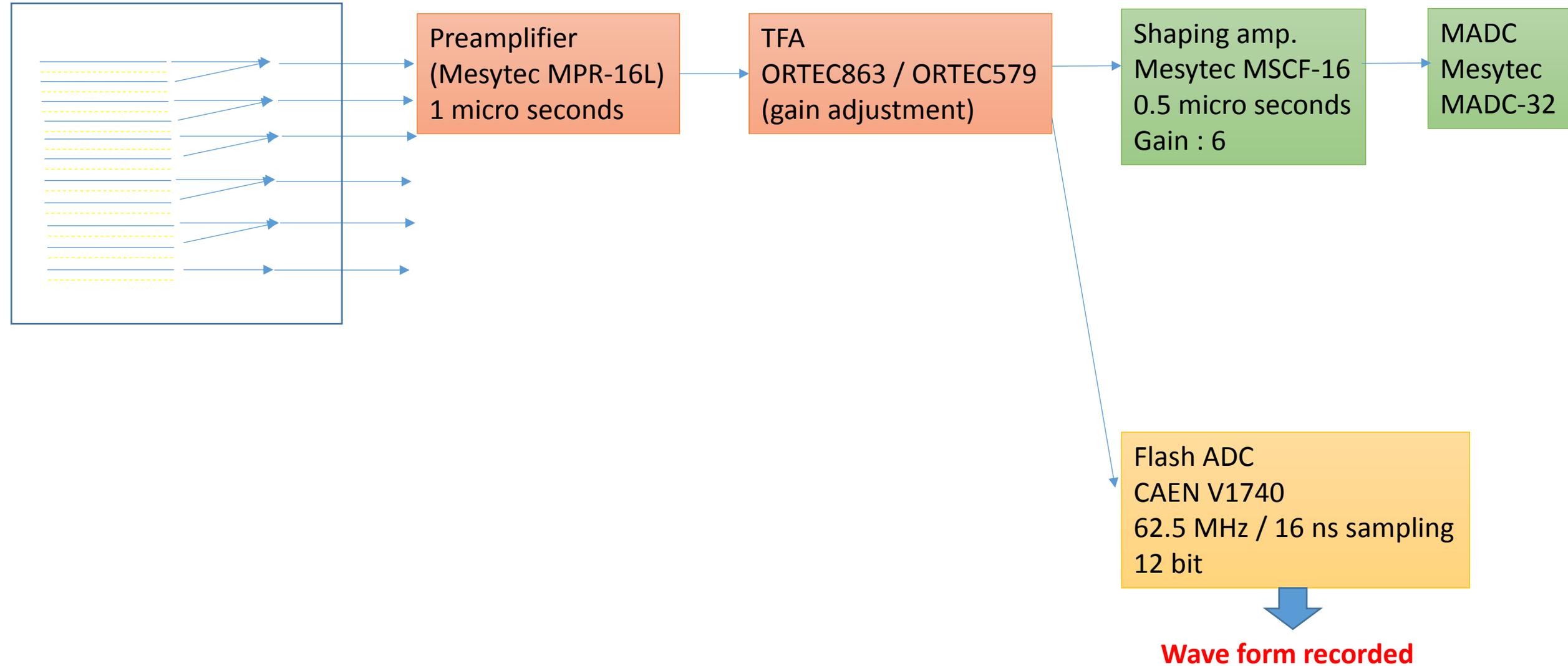
- Goal
  - Removing contributions from pile up noises from the signals for ionization chamber irradiated a high rate RI beam with an intensity of around **a few  $10^5$  cps**
    - ( $\leftarrow \rightarrow$  a conventional way: preamp + shaper  $\rightarrow$  high rejection rate (33% survival rate @ the above intensity))
  - Establish the method and apply it to other detectors in the beam line

# Ion chamber (D. Nishimura, Tokyo University of Science)



- Atmospheric pressure
  - Voltage +400V
  - Gas : try two kinds P10 and CF4
  - Length : 440 mm
  - Drift length : 2 cm (→ drift time : 360 – 400 ns at this voltage)
  - Active area : 200 mm phi
- 
- Resolution achieved with a low rate and without digitizer  
5 sigma separation for  $Z \sim 50$  @  $\sim 200$  MeV/u

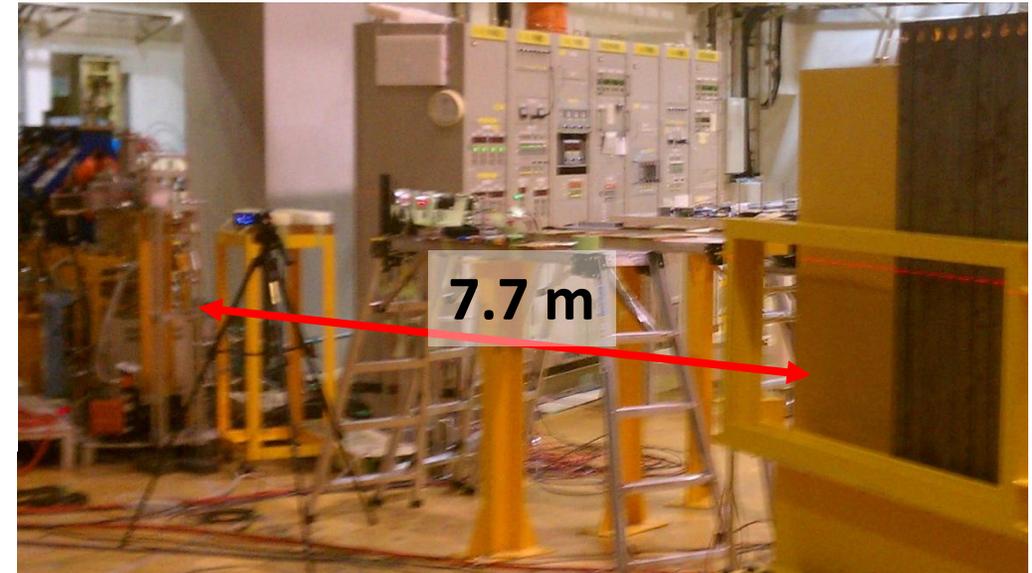
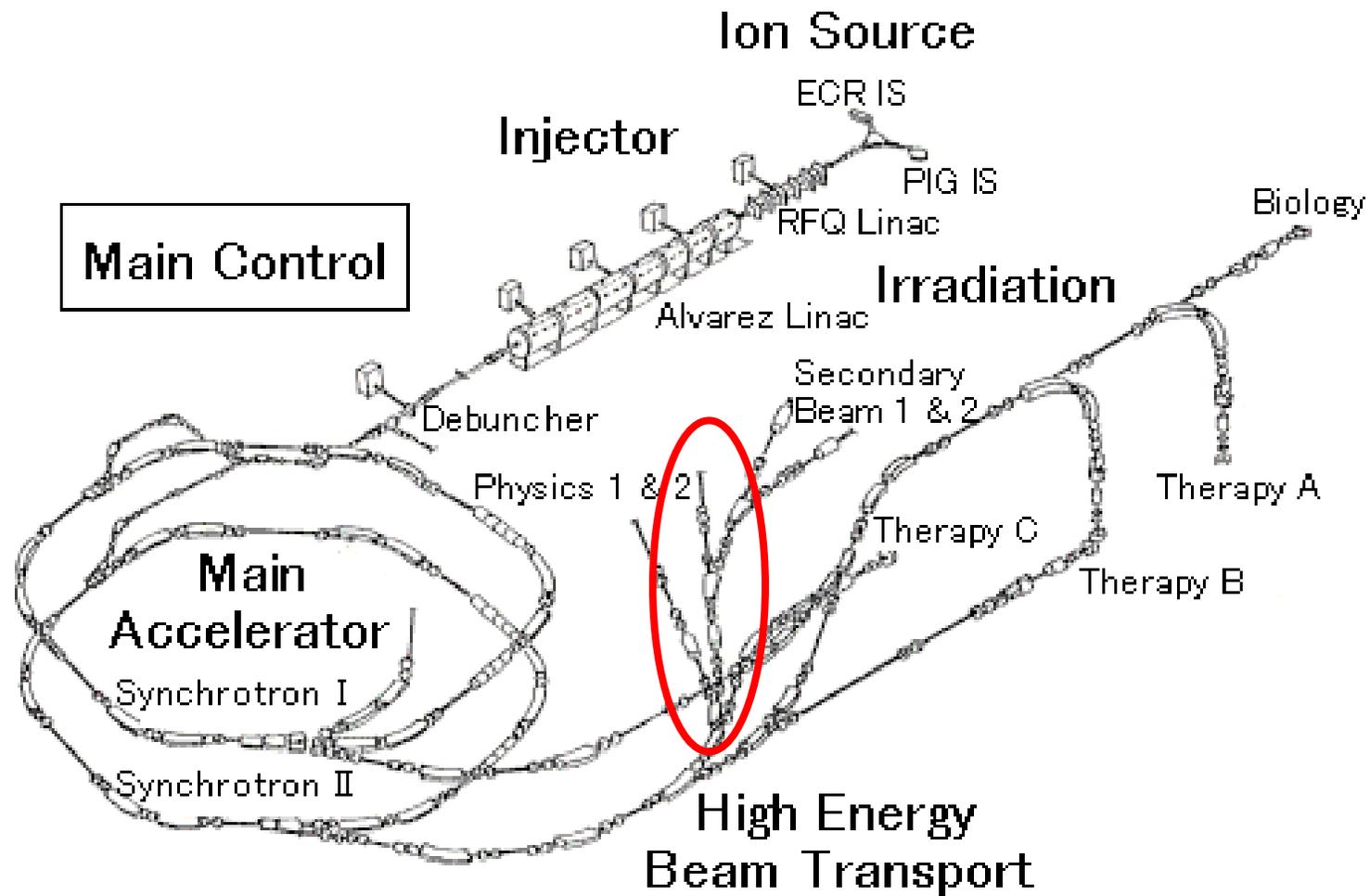
# Electronics & DAQ



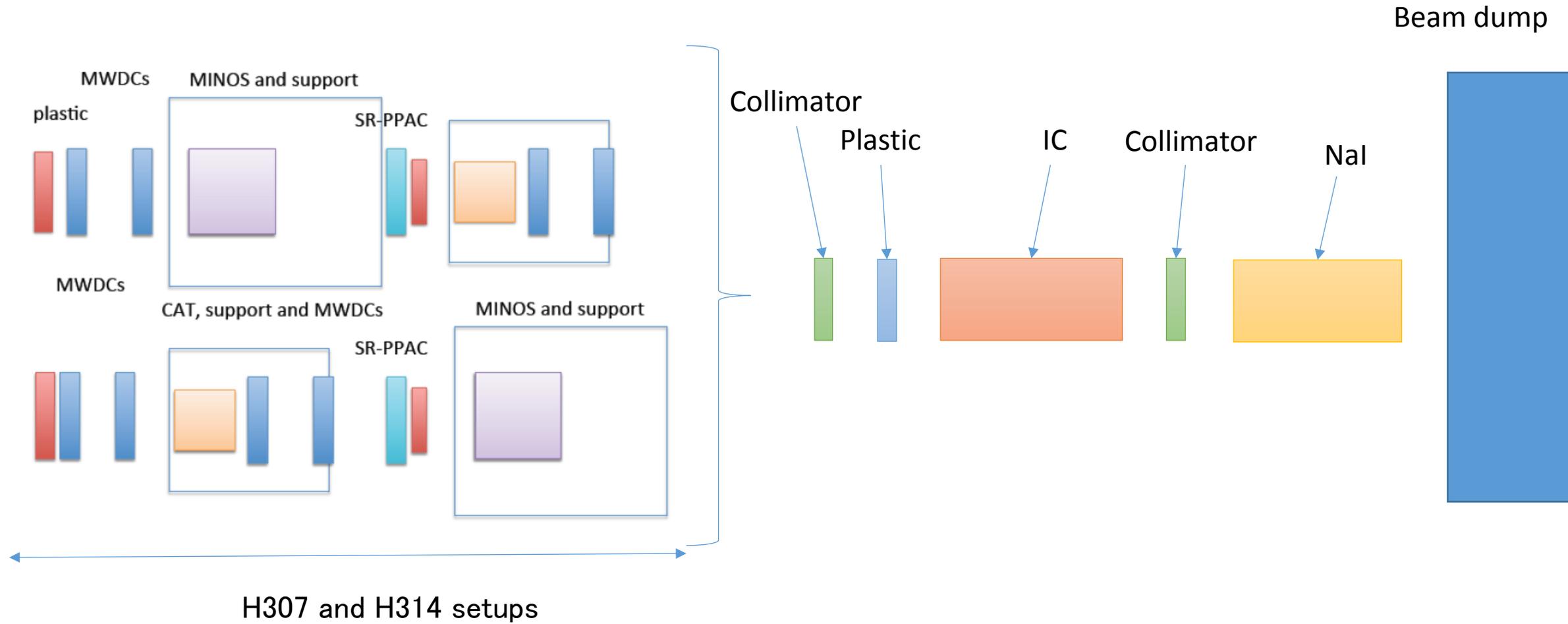
# Beams

- Ne beam @ 180 A MeV ~50k, ~150k, 600k, 1.5M ppp
- Xe beam @ 200 A MeV ~10k, ~50k, ~500k ppp
  
- Spill interval and width : 3 and 1 s

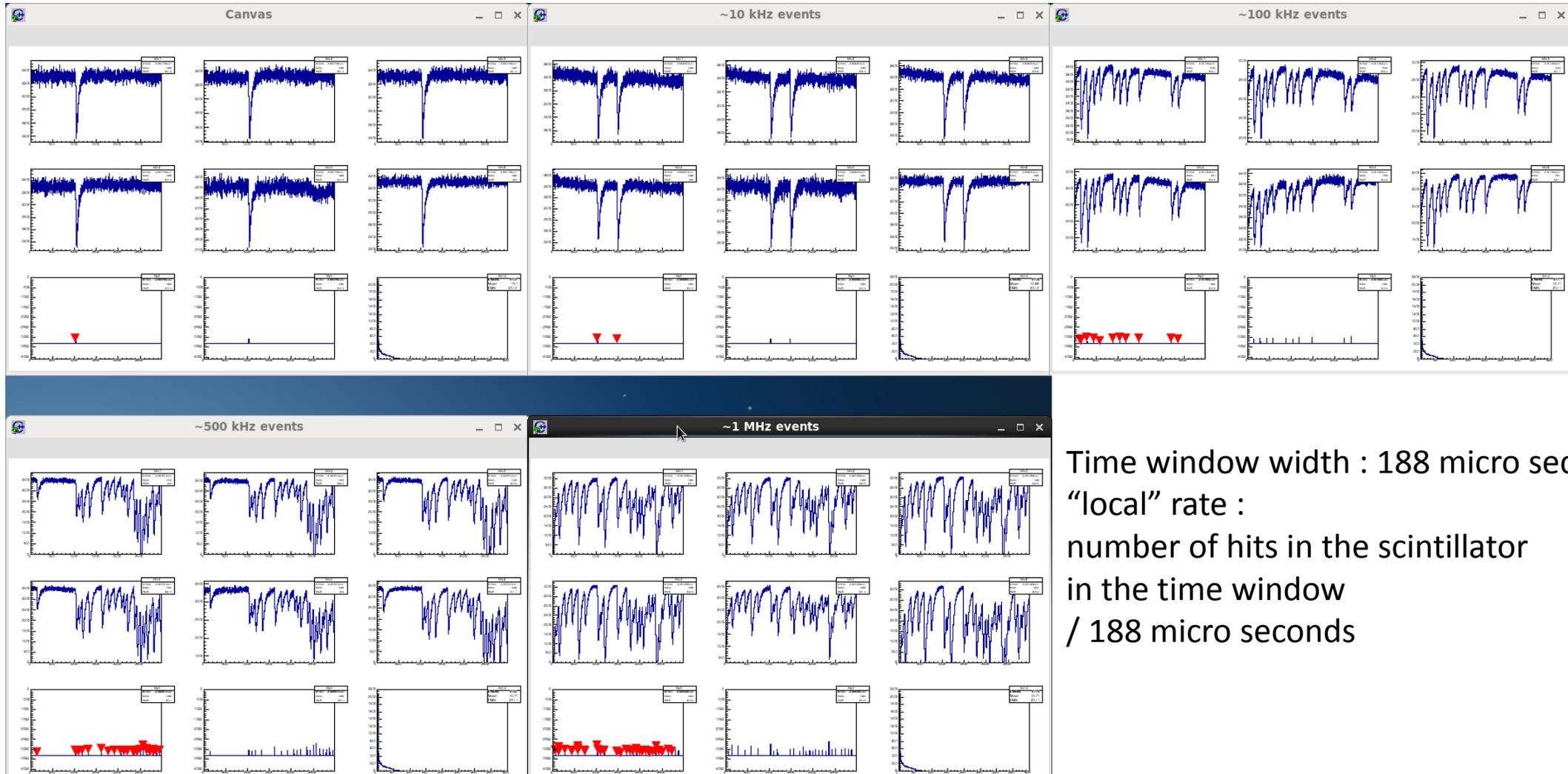
# Beam line



# Setup

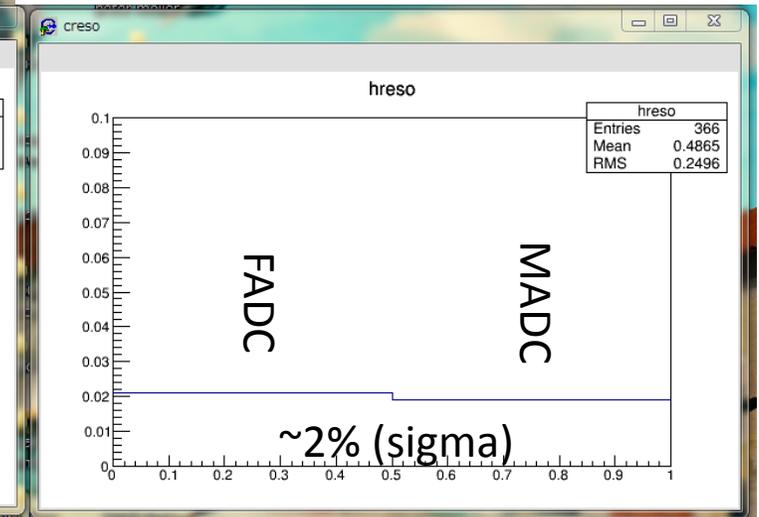
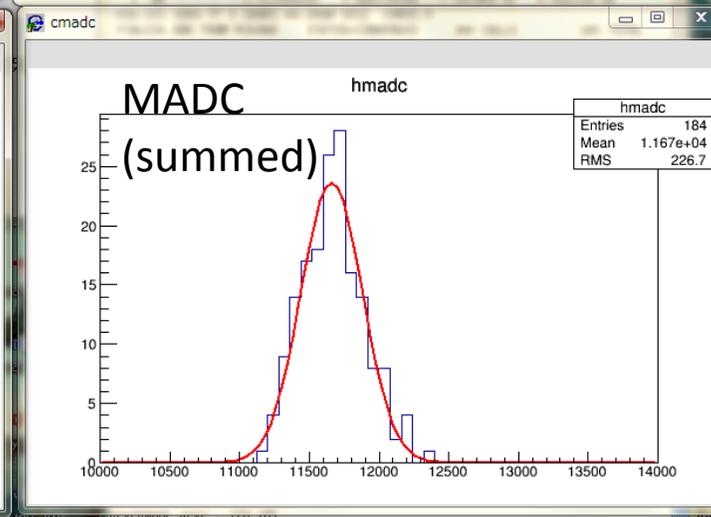
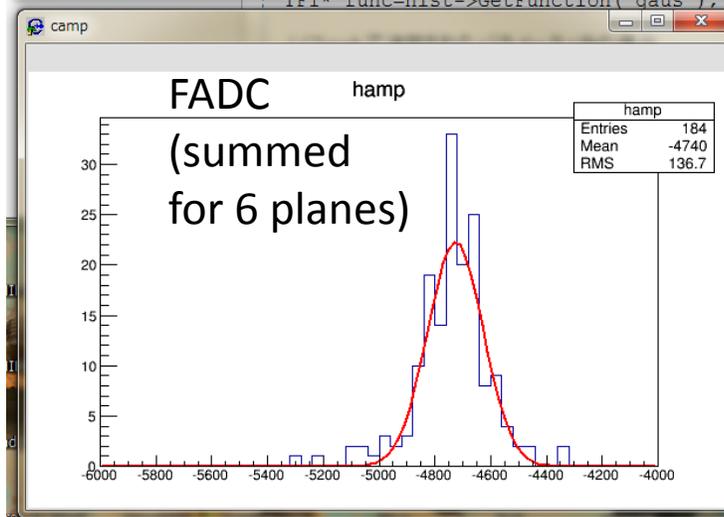
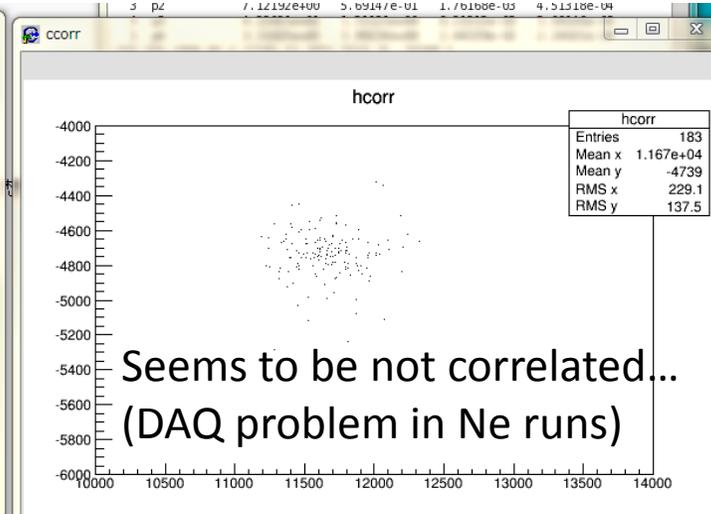
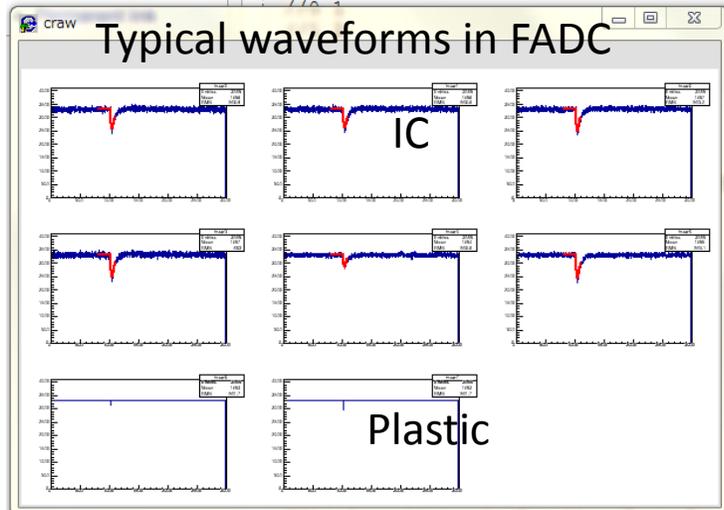


# Typical recorded waveforms and “local” beam rate definition

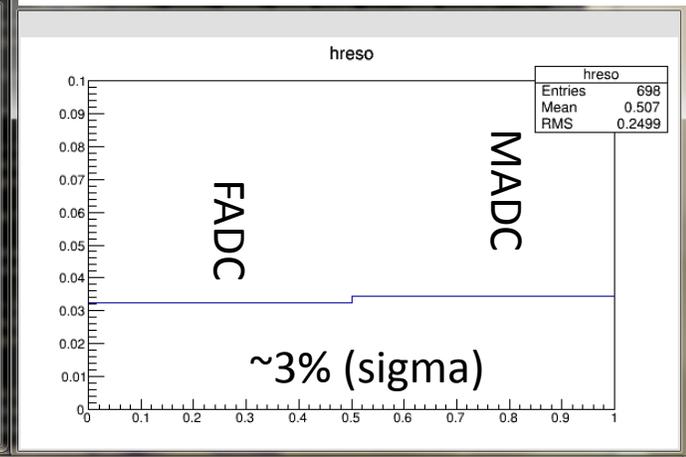
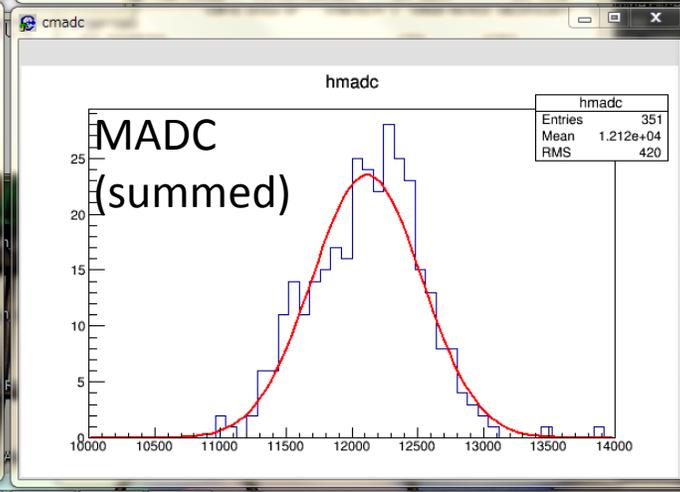
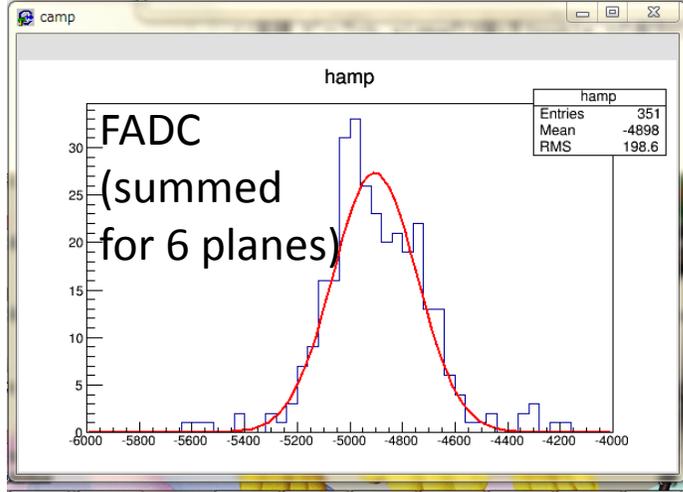
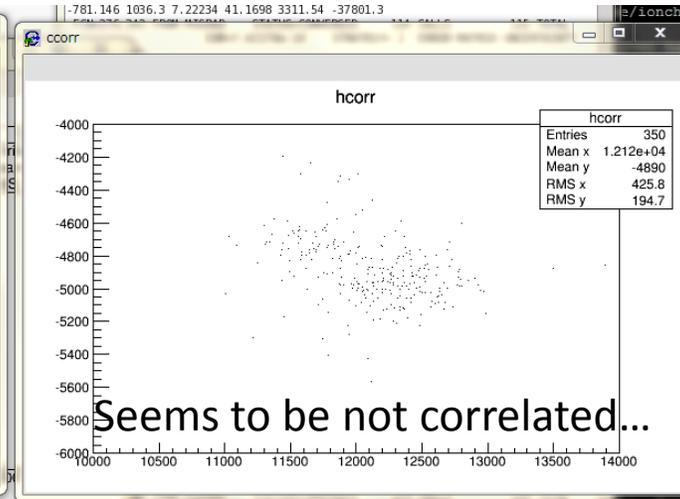
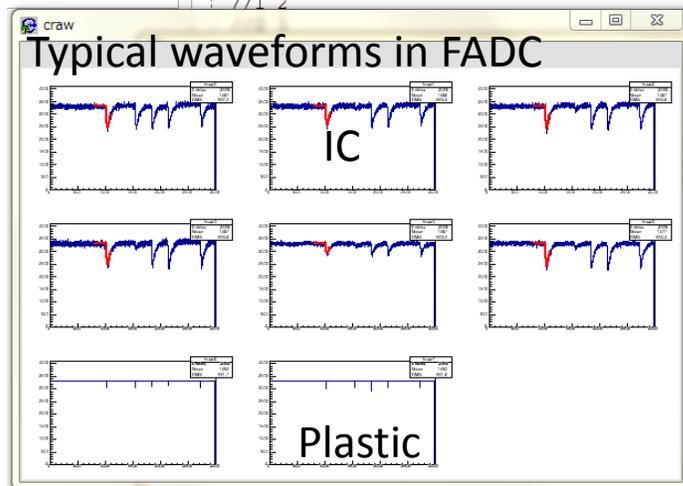


Time window width : 188 micro seconds  
“local” rate :  
number of hits in the scintillator  
in the time window  
/ 188 micro seconds

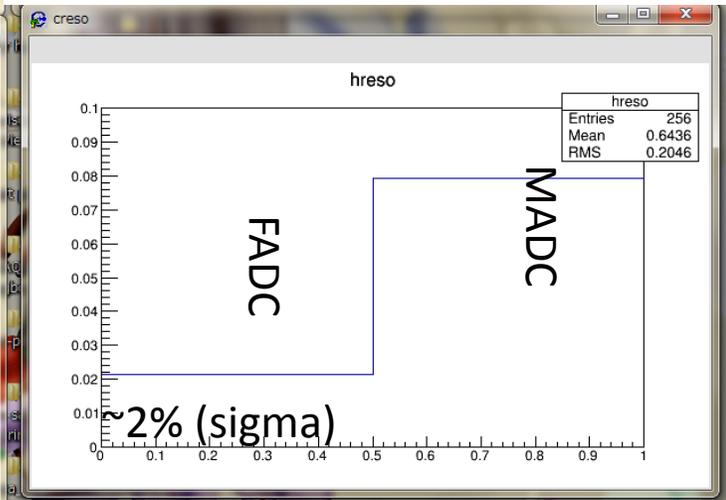
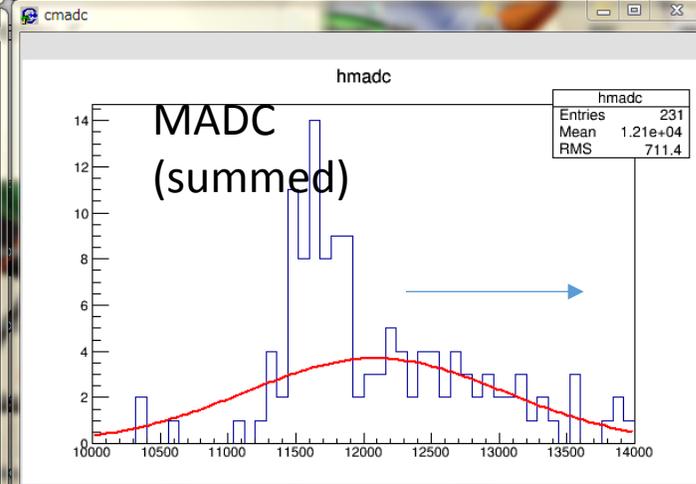
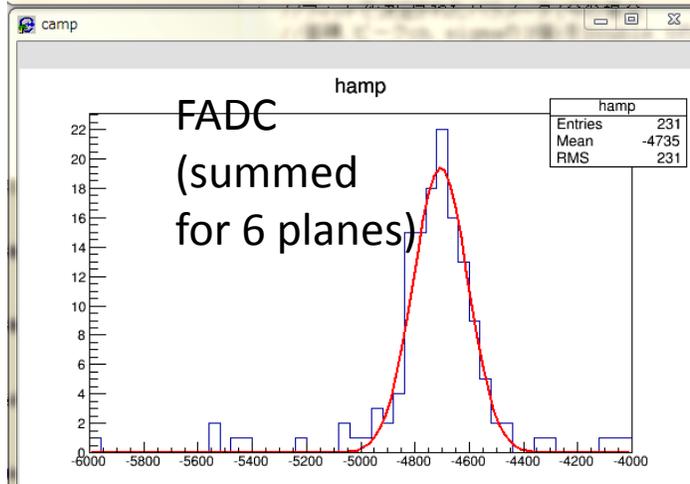
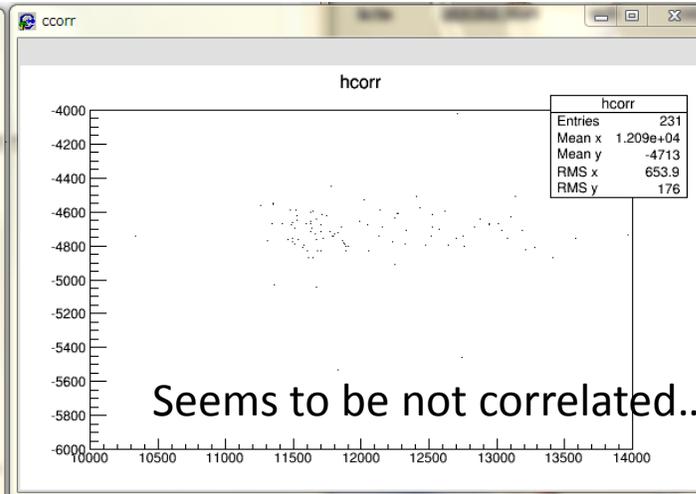
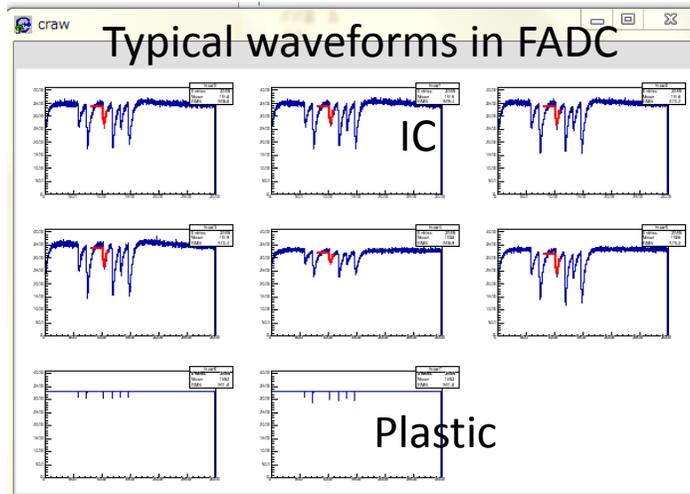
@ 50 kppp, HV(IC)=400 V, Preamplifier 1 micro sec., 20Ne @ 180 AMeV, P10 gas (RUN149)



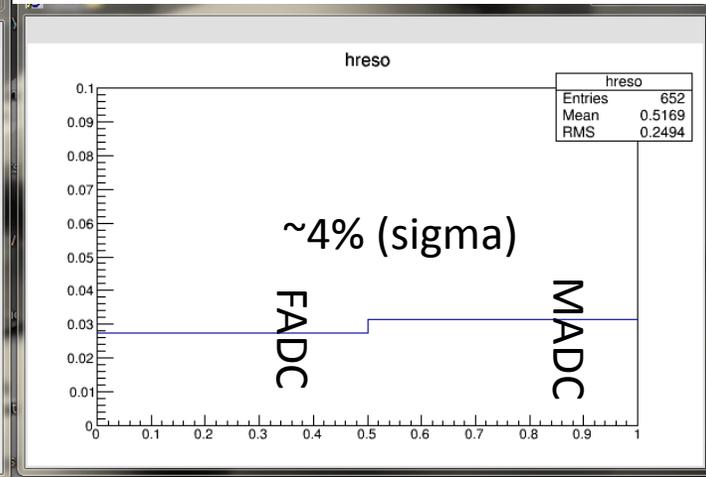
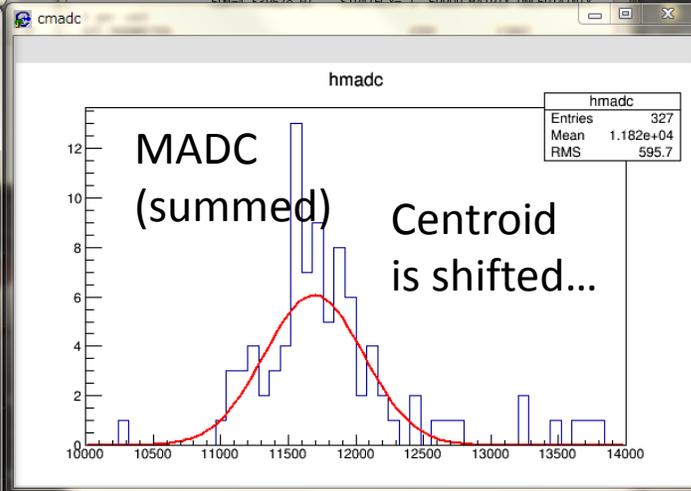
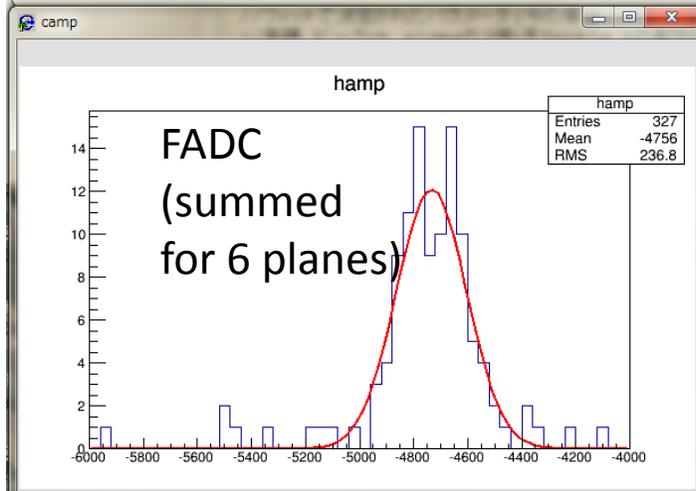
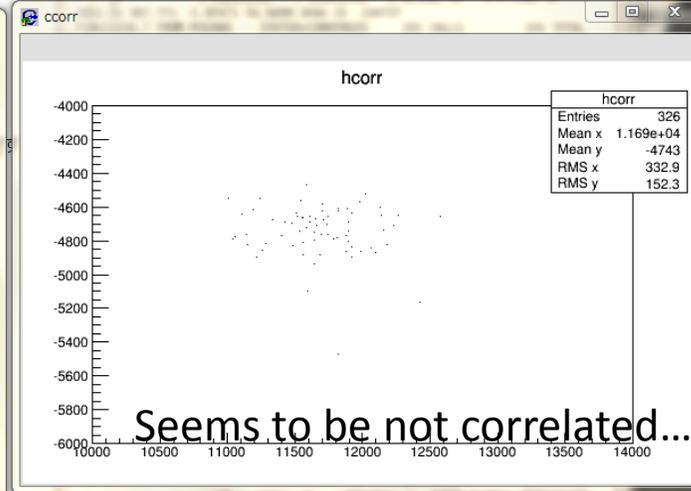
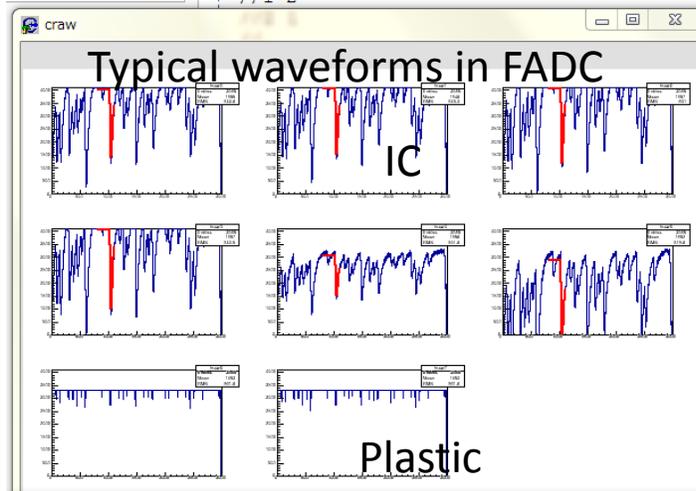
@ 150 kppp, HV(IC)=400 V, Preamplifier 1 micro sec., 20Ne @ 180 AMeV, P10 gas (RUN163)



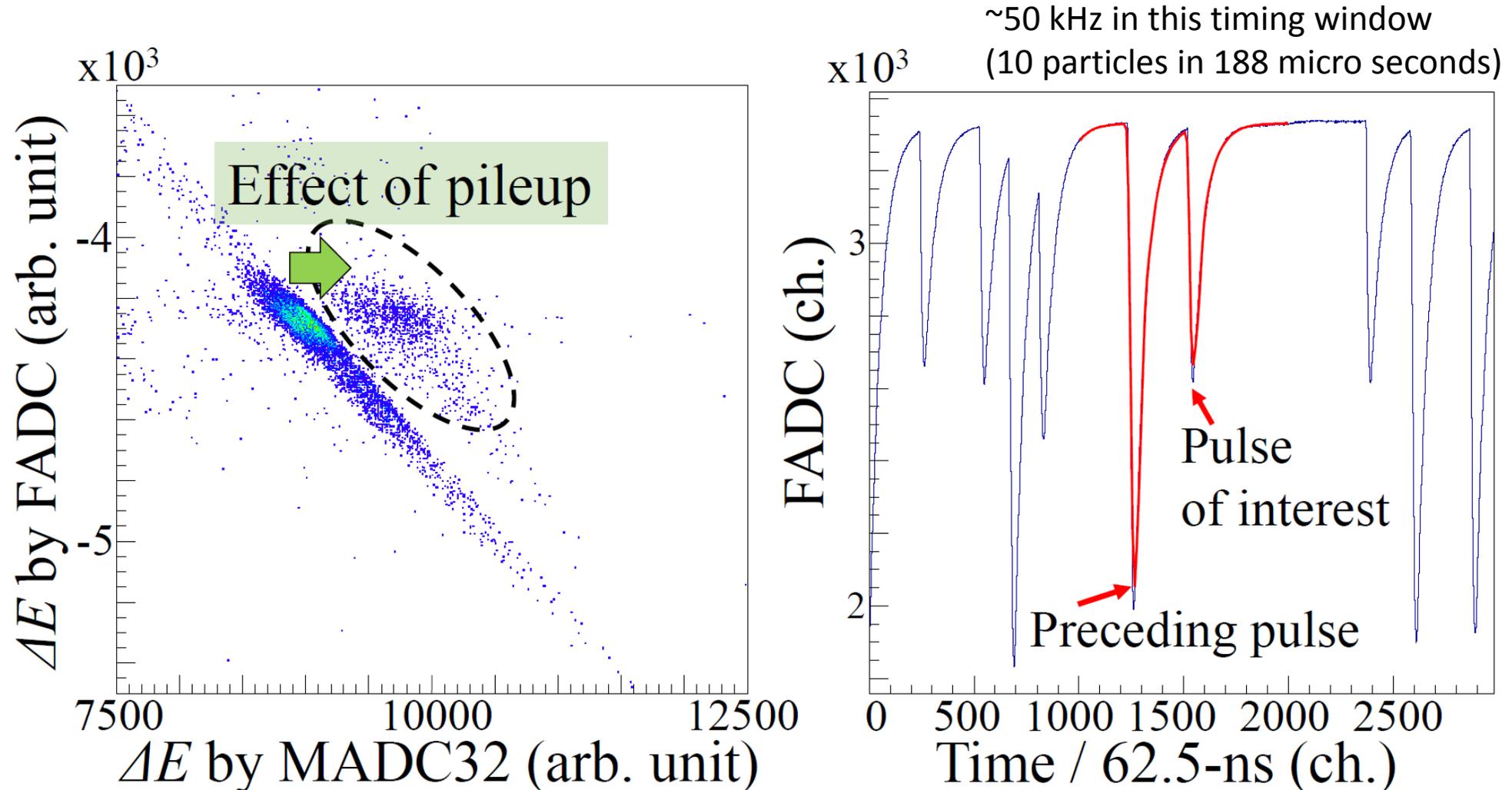
@ 600 kppp, HV(IC)=400 V, Preamplifier 1 micro sec., 20Ne @ 180 AMeV, P10 gas (RUN162)



@ 1.5 Mppp, HV(IC)=400 V, Preamplifier 1 micro sec., 20Ne @ 180 AMeV, P10 gas (RUN161)



# Xe @ 50 kppp (DAQ synchronization fixed...)



# Summary & outlook

- IC readout : preamp time constant 1 micro seconds + 62.5 ns sampling rate with 12 bit FADC



- Gives a resolution similar to the method using preamp. + shaping amp + peak-sensitive ADC
- Save pile up events up to ~100 kHz

- Energy resolution in Xe runs will be evaluated
- $>5 \times 10^5$  Hz
- preamplifier with 1 micro seconds (drift time ~400 ns) is not enough (large baseline shift / saturation)
- The limit of this method (drift along the beam direction)
- Segmentation, vertical drift, ...
- Fast data throughput